

Search Notes

Application/Control No.

10/774,011

Examiner

John E. Chapman

Applicant(s)/Patent under
Reexamination

WU ET AL.

Art Unit

2856

SEARCHED

Class	Subclass	Date	Examiner
73	514.33		
	514.36		
	514.37		
	514.16		
	514.01		
	714		
	727	6/24/2005	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR